

“StatSTEM: An efficient program for accurate and precise model-based quantification of atomic resolution electron microscopy images”. De Backer A, van den Bos KHW, Van den Broek W, Sijbers J, Van Aert S, Journal of physics : conference series T2 - Electron Microscopy and Analysis Group Conference 2017 (EMAG2017), 3-6 July 2017, Manchester, UK **902**, 012013 (2017). <http://doi.org/10.1088/1742-6596/902/1/012013>